# International Rectifier

# IRL2203NPbF

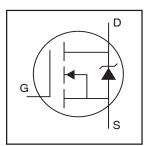
HEXFET® Power MOSFET

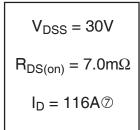
- Advanced Process Technology
- Ultra Low On-Resistance
- Dynamic dv/dt Rating
- 175°C Operating Temperature
- Fast Switching
- Fully Avalanche Rated
- Lead-Free

#### **Description**

Advanced HEXFET® Power MOSFETs from International Rectifier utilize advanced processing techniques to achieve extremely low on-resistance per silicon area. This benefit, combined with the fast switching speed and ruggedized device design that HEXFET power MOSFETs are well known for, provides the designer with an extremely efficient and reliable device for use in a wide variety of applications.

The TO-220 package is universally preferred for all commercial-industrial applications at power dissipation levels to approximately 50 watts. The low thermal resistance and low package cost of the TO-220 contribute to its wide acceptance throughout the industry.







#### **Absolute Maximum Ratings**

	Parameter	Max.	Units
I <sub>D</sub> @ T <sub>C</sub> = 25°C	Continuous Drain Current, V <sub>GS</sub> @ 10V	116⑦	
I <sub>D</sub> @ T <sub>C</sub> = 100°C	Continuous Drain Current, V <sub>GS</sub> @ 10V	82	Α
I <sub>DM</sub>	Pulsed Drain Current ①	400	
P <sub>D</sub> @T <sub>C</sub> = 25°C	Power Dissipation	180	W
	Linear Derating Factor	1.2	W/°C
$V_{GS}$	Gate-to-Source Voltage	± 16	V
I <sub>AR</sub>	Avalanche Current①	60	Α
E <sub>AR</sub>	Repetitive Avalanche Energy①	18	mJ
dv/dt	Peak Diode Recovery dv/dt ③	5.0	V/ns
T <sub>J</sub>	Operating Junction and	-55 to + 175	
T <sub>STG</sub>	Storage Temperature Range		°C
	Soldering Temperature, for 10 seconds	300 (1.6mm from case )	
	Mounting torque, 6-32 or M3 srew	10 lbf•in (1.1N•m)	

#### **Thermal Resistance**

	Parameter	Тур.	Max.	Units
R <sub>θJC</sub>	Junction-to-Case		0.85	
R <sub>θCS</sub>	Case-to-Sink, Flat, Greased Surface	0.50		°C/W
$R_{\theta JA}$	Junction-to-Ambient		62	

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## Electrical Characteristics @ T<sub>J</sub> = 25°C (unless otherwise specified)

	Parameter	Min.	Тур.	Max.	Units	Conditions
V <sub>(BR)DSS</sub>	Drain-to-Source Breakdown Voltage	30			V	$V_{GS} = 0V, I_D = 250\mu A$
$\Delta V_{(BR)DSS}/\Delta T_J$	Breakdown Voltage Temp. Coefficient		0.029		V/°C	Reference to 25°C, I <sub>D</sub> = 1mA
	0.5 5			7.0		V <sub>GS</sub> = 10V, I <sub>D</sub> = 60A ④
R <sub>DS(on)</sub>	Static Drain-to-Source On-Resistance			10	mΩ	V <sub>GS</sub> = 4.5V, I <sub>D</sub> = 48A ④
V <sub>GS(th)</sub>	Gate Threshold Voltage	1.0			V	$V_{DS} = V_{GS}$ , $I_D = 250\mu A$
g <sub>fs</sub>	Forward Transconductance	73			S	V <sub>DS</sub> = 25V, I <sub>D</sub> = 60A⊕
	D :			25	μА	V <sub>DS</sub> = 30V, V <sub>GS</sub> = 0V
I <sub>DSS</sub>	Drain-to-Source Leakage Current			250		V <sub>DS</sub> = 24V, V <sub>GS</sub> = 0V, T <sub>J</sub> = 125°C
	Gate-to-Source Forward Leakage			100	nA	V <sub>GS</sub> = 16V
I <sub>GSS</sub>	Gate-to-Source Reverse Leakage			-100	IIA	V <sub>GS</sub> = -16V
Qg	Total Gate Charge			60		I <sub>D</sub> = 60A
Q <sub>gs</sub>	Gate-to-Source Charge			14	nC	$V_{DS} = 24V$
Q <sub>gd</sub>	Gate-to-Drain ("Miller") Charge			33		$V_{GS} = 4.5V$ , See Fig. 6 and 13
t <sub>d(on)</sub>	Turn-On Delay Time		11			V <sub>DD</sub> = 15V
t <sub>r</sub>	Rise Time		160			$I_D = 60A$
t <sub>d(off)</sub>	Turn-Off Delay Time		23			$R_G = 1.8\Omega$
t <sub>f</sub>	Fall Time		66			V <sub>GS</sub> = 4.5V, See Fig. 10 ④
L <sub>D</sub>	Internal Drain Inductance		4.5			Between lead,
						6mm (0.25in.)
L <sub>S</sub>	Internal Source Inductance		7.5		nH	from package
						and center of die contact
C <sub>iss</sub>	Input Capacitance		3290			$V_{GS} = 0V$
Coss	Output Capacitance		1270			$V_{DS} = 25V$
C <sub>rss</sub>	Reverse Transfer Capacitance		170		pF	f = 1.0MHz, See Fig. 5
E <sub>AS</sub>	Single Pulse Avalanche Energy@		1320©	290⑥	mJ	I <sub>AS</sub> = 60A, L = 0.16mH

#### **Source-Drain Ratings and Characteristics**

	Parameter	Min.	Тур.	Max.	Units	Conditions		
Is	Continuous Source Current			1100		MOSFET symbol		
	(Body Diode)	116	116⑦	Α	showing the			
I <sub>SM</sub>	Pulsed Source Current			- 400	400	400		integral reverse
	(Body Diode)①		400		00	p-n junction diode.		
V <sub>SD</sub>	Diode Forward Voltage			1.2	V	$T_J = 25^{\circ}C$ , $I_S = 60A$ , $V_{GS} = 0V$ ④		
t <sub>rr</sub>	Reverse Recovery Time		56	84	ns	$T_J = 25^{\circ}C, I_F = 60A$		
Q <sub>rr</sub>	Reverse Recovery Charge		110	170	nC	di/dt = 100A/µs ④		
t <sub>on</sub>	Forward Turn-On Time	Intrinsic turn-on time is negligible (turn-on is dominated by L <sub>S</sub> +L <sub>D</sub> )						

#### Notes:

- ① Repetitive rating; pulse width limited by max. junction temperature. ( See fig. 11 )
- ② Starting  $T_J = 25$ °C, L = 0.16mH  $R_G = 25\Omega$ ,  $I_{AS} = 60$ A,  $V_{GS} = 10$ V (See Figure 12)
- $\label{eq:loss} \begin{array}{l} \text{ } 3 \text{ } I_{SD} \leq 60A, \text{ di/dt} \leq 110A/\mu s, \text{ } V_{DD} \leq V_{(BR)DSS}, \\ T_{J} \leq 175^{\circ}C \end{array}$
- 4 Pulse width  $\leq 400 \mu s$ ; duty cycle  $\leq 2\%$ .
- ⑤ This is a typical value at device destruction and represents operation outside rated limits.
- $\ \, \mbox{\ \ \, } \mbox{\ \ } \mbox{\$
- O Calculated continuous current based on maximum allowable junction temperature. Package limitation current is 75A.

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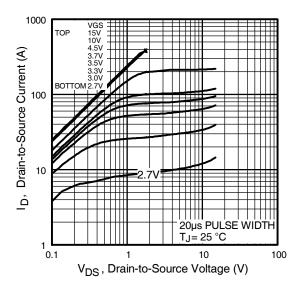


Fig 1. Typical Output Characteristics

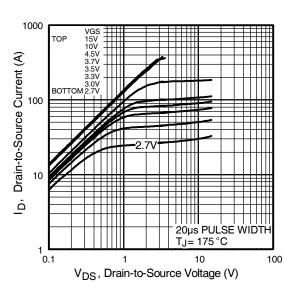


Fig 2. Typical Output Characteristics

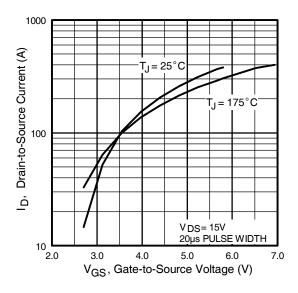
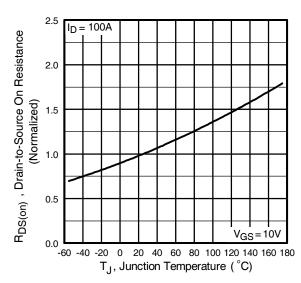
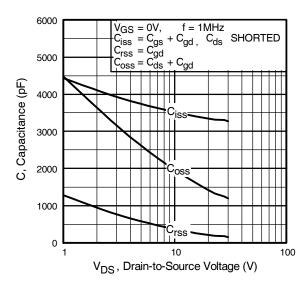


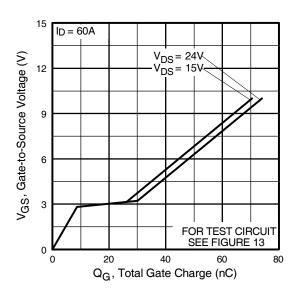
Fig 3. Typical Transfer Characteristics



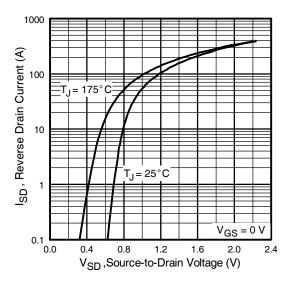
**Fig 4.** Normalized On-Resistance Vs. Temperature



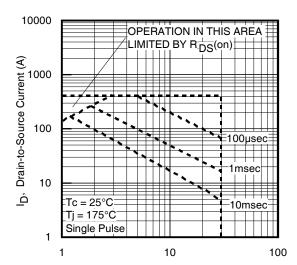
**Fig 5.** Typical Capacitance Vs. Drain-to-Source Voltage



**Fig 6.** Typical Gate Charge Vs. Gate-to-Source Voltage

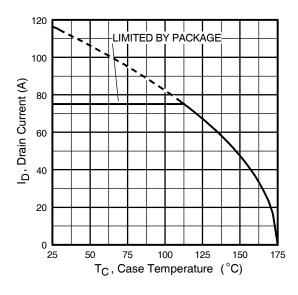


**Fig 7.** Typical Source-Drain Diode Forward Voltage



V<sub>DS</sub> , Drain-toSource Voltage (V) **Fig 8.** Maximum Safe Operating Area

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**Fig 9.** Maximum Drain Current Vs. Case Temperature

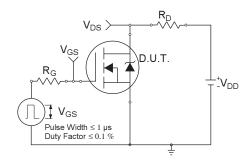


Fig 10a. Switching Time Test Circuit

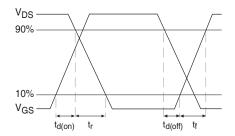


Fig 10b. Switching Time Waveforms

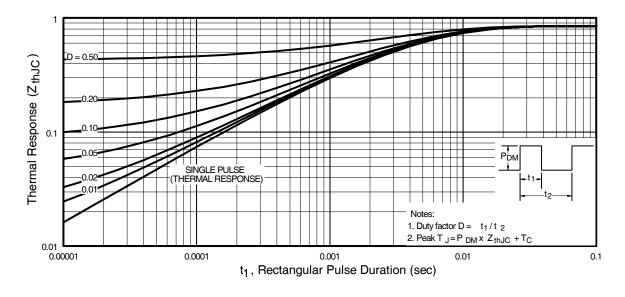


Fig 11. Maximum Effective Transient Thermal Impedance, Junction-to-Case

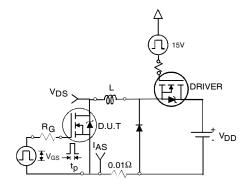


Fig 12a. Unclamped Inductive Test Circuit

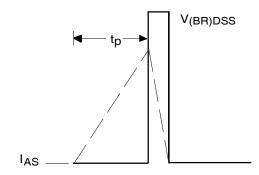


Fig 12b. Unclamped Inductive Waveforms

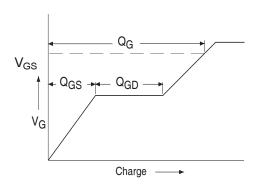


Fig 13a. Basic Gate Charge Waveform

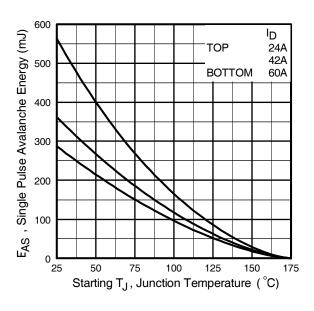


Fig 12c. Maximum Avalanche Energy Vs. Drain Current

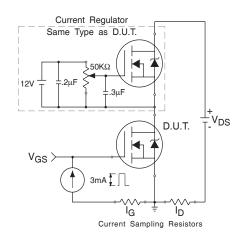
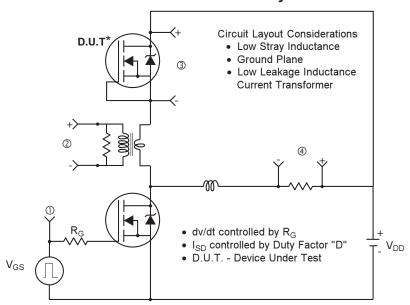


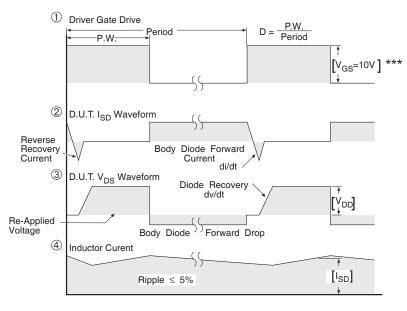
Fig 13b. Gate Charge Test Circuit

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#### Peak Diode Recovery dv/dt Test Circuit



\* Reverse Polarity of D.U.T for P-Channel

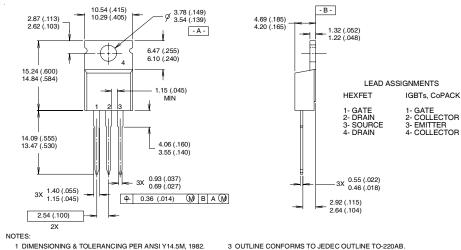


\*\*\*  $V_{GS}$  = 5.0V for Logic Level and 3V Drive Devices

Fig 14. For N-channel HEXFET® power MOSFETs

### TO-220AB Package Outline

Dimensions are shown in millimeters (inches)



- 4 HEATSINK & LEAD MEASUREMENTS DO NOT INCLUDE BURRS.

## TO-220AB Part Marking Information

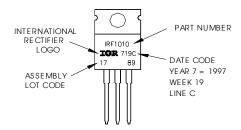
EXAMPLE: THIS IS AN IRF1010

LOT CODE 1789

ASSEMBLED ON WW 19, 1997 IN THE ASSEMBLY LINE "C"

Note: "P" in assembly line

position indicates "Lead-Free"



Data and specifications subject to change without notice. This product has been designed and qualified for the industrial market. Qualification Standards can be found on IR's Web site.



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